

Notice of References Cited	Application/Control No. 10/738,910	Applicant(s)/Patent Under Reexamination DARDIK ET AL.	
	Examiner John P. Sheehan	Art Unit 1742	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-3,759,635	09-1973	Carter et al.	417/50
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	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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